



TS IEC 62804: draft 2013-12

Test Method for Detection of Potential Induced Degradation (PID) of Photovoltaic (PV)-Modules

Ref.: 5011404-3972-0001/212183

Applicant: Wuxi Suntech Power Co., Ltd.
12 Xin Hua Road, 214028 Wuxi City, China

Product: Crystalline silicon Photovoltaic (PV)-Modules

Type: A) STPXXX-16/Tem
B) STPXXX-24/Vem
B) STPXXXS-24/Vem
C) STPXXX-20/Wem
C) STPXXXS-20/Wem

XXX in the type replaces the power in watt and can be any number between:

180 - 230 for A)
220 - 350 for B)
210 - 290 for C)

Manufacturer: Wuxi Suntech Power Co., Ltd.

Standard: TS IEC 62804: draft 2013-12, modified

Test conditions

Testing time: 96 h

Chamber temperature: 85°C

Relative Humidity: 85 %

Potential to ground: - 1000 V

Pass criteria

Power degradation: < 5%

Dry Insulation: > 40 MΩm²

Wet insulation: > 40 MΩm²





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Summary of test results:

Maximum power degradation: required max. 5 %
measured max. 2.39 %

The measured degradation is below the allowed degradation.

Dry insulation resistance: required 30.5 M Ω for A)
20.6 M Ω for B)
24.5 M Ω for C)
measured >500 M Ω

The measured dry insulation resistance is above the limit.

Wet insulation resistance: required 30.5 M Ω for A)
20.6 M Ω for B)
24.5 M Ω for C)
measured >500 M Ω

The measured wet insulation resistance is above the limit.

Visual inspection: No findings

The complete test results are given in: Testreport-212183-ET2-1.

VDE Prüf- und Zertifizierungsinstitut GmbH

VDE Testing and Certification Institute

Fachgebiet ET2 / Section ET2

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